



Test probes




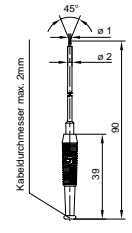

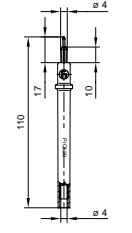

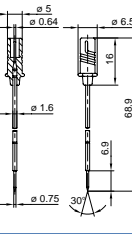

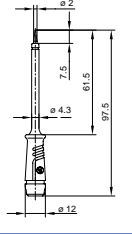

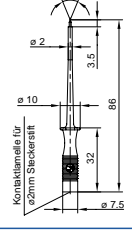

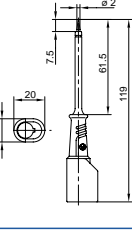

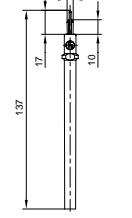

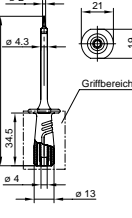
Product description

Test probes are used for voltage testing purposes.

Their needle-like steel tips penetrate oxidation layers, thereby establishing an effective connection with the test specimen.

The spring-loaded prods of the MICRO-PRUEF and PRUEF 2610 FT make contact with sensitive components with gently applied spring force. Contact with less vulnerable contact points can be established with the PRUEF 2700, which is

also equipped with a 4 mm pin. The SS 260 prod guard protects the user from injury and ICs from short circuits.

| *System Article type | Technical Data | Order no. Colour | *System Article type | Technical Data | Order no. Colour |
|---|---|--|---|---|--|
|  PRUEF 1 |  Kabeldurchmesser max. 2mm | Solder contact 931 376-100 ● 931 376-101 ● |  PRUEF 20 |  | 973 505-100 ● 973 505-101 ● |
|  MICRO-PRUEF MPS 2/0,64 FT |  | Sprung probe tip 973 995-100 ● 973 995-101 ● |  PRUEF 2 |  | 973 368-100 ● 973 368-101 ● |
|  MPS 1 |  Kontaktschäfte für 20mm Steckkarte | 973 531-100 ● 973 531-101 ● |  PRUEF 2 S |  | 973 659-100 ● 973 659-100 ● |
|  PRUEF 10 |  | Solder contact 930 227-100 ● 930 227-101 ● |  PRUEF 2600 |  Griffbereich | 972 317-100 ● 972 317-101 ● |

* System: (64) = 0.64 mm system / (2) ≅ 2 mm system / (4) ≅ 4 mm system / (●) ≅ 4 mm safety system / (↔) ≅ 4 mm sliding sleeve system